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LOW-NOISE, 10.7 GHz, COOLED, GASFET AMPLIFIER

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Table of Contents

I.	Introduction	•	•	•	•	•	•	•	•	•	•		•	•	•	•				•	•	•	•	•	•	•		•	•	3
II.	Description	•	•	•	•	•	•		•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	3
III.	Results	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	7

Figures

Figure 1	Schematic of Single-Stage of 3-Stage Amplifier	•	•	•	•	• •	•	4
Figure 2	Photograph of 3-Stage Amplifier	•	•	•	•	• •	•	5
Figure 3	Amplifier Characteristics at 300K and 15K	•	•	•	•		•	9

Tables

Table	I.	Measured	Noise	Parameters	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	8
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Appendices

Appendix 1	10.7 GHz Amplifier Drawings	
	A. Module, A2613M40	.1
	B. Connectors, Modifications, A2613M41 1	.2
	C. Coaxial Transformers, A2613M42	2
	D. Input Section, A2613M43	.3
	E. Output Section, A2613M44	.3
	F. Interstage Pins & Coax Line Supports, A2613M45 1	.4
	G. Power Connector Spacer & Module Screw, A2613M46 1	.4
	H. Tuning Cover, A2613M47	.5
	I. Source Lead Clamp, A2613M48	.5
	J. Test Cover, A2613M49	.6
	K. Lid, A2613M50	.6

References	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	•	10

LOW-NOISE 10.7 GHz COOLED GASFET AMPLIFIER

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I. Introduction

A three-stage gallium-arsenide field effect transistor amplifier giving a noise temperature of 29K (0.4 dB noise figure) at a physical temperature of 13K is described. The amplifier utilizes a novel modular construction with coaxial air-lines, sliding $\lambda/4$ transformers, and packaged NE13783 and MGF1403 FET's. Noise parameters of these devices at 300K and 13K are reported.

II. Description

A coupling network which can transform a 50 ohm source or load to any desired impedance consists of a $\lambda/4$ transmission line with characteristic impedance Z₁ in cascade with a transmission line of length, L, and characteristic impedance of 50 ohms as shown in Figure 1. A microstrip realization of this network utilizin $\varepsilon = 2.2$ dielectric with thickness = .25 mm was first tried but was abandoned in favor of the coaxial-line network shown in Figure 2. The coaxial-lines had been used in a previous 5 GHz amplifier [1] and were superior from the standpoint of loss and adjustability. The real part of impedance is varied by changing the diameter and surrounding dielectric of the sliding $\lambda/4$ slug; the distance, L, between this slug and the FET determines the reactance (and hence resonant frequency) of the coupling network. The distance also affects the real part of the impedance, but for L < $\lambda/16$ (as is the case for the FET's used in the 10 to 15 GHz range) the effect is small. A center conductor diameter of 1.25 mm in a 2.74 mm square outer conductor groove is used for the main 50 ohm transmission



Schematic of single-stage of three-stage amplifier. The quantity, D, in the tables is the diameter in mm of the $\lambda/4$ transformer inner-conductor which is surrounded by PTFE when denoted by * after the D value. Fig. 1.



line; the characteristic impedance of this geometry is given in [2]. A flat cover forms one wall of the outer conductor and may have adjustment slots without affecting performance significantly. Values of Z_1 , slug diameter, and L appropriat for a 3-stage amplifier with a NE13783 first stage and MGF1403 second and third stages are given in Figure 1.

Convenient low-loss DC blocking capacitors can be formed by inserting the FET gate and drain leads into holes lined with #22 PTFE tubing (0.D. = .94 mm, I.D. = .43 mm) in the ends of the 1.25 mm diameter center conductors. A capacitanc of .12 pf per mm of insertion length was measured at 1 MHz. The re-entrant transmission line formed in this way has an approximate characteristic impedance of 39 ohms, relative propagation velocity of 0.72, and an open-circuited end fringing capacitance of .04 pf. For the 10.7 GHz amplifier described here, the gate and drain leads are cut to 4.6 mm, and 4.3 mm is inserted within the center conductor; the resulting series reactance is -5 ohms. For higher frequency amplifiers, the length is cut shorter giving sufficient capacitive reactance to tune out the parasitic lead inductance of the FET. DC bias is carried to the FET by .13 mm diameter wires of approximate length $\lambda/4$ soldered between the FET lead and chip bypass capacitors. A small toroid [3] is placed around the drain bias wire of stage 2 to suppress a 15 GHz oscillation of the cooled amplifier.

The two source leads of the packaged FET are grounded through slotted clamps which are movable to allow an adjustable source inductance to be realized. These leads can be adjusted to optimize input and output match as described in [4] and [5]. The clamps become tight as the top cover is fastened to the amplifier chassis. Each stage of the three-stage amplifier is a separable module which can be tested and aligned before assembly. The center conductor is bonded with a cyano-acrylate adhesive to a 1.25 mm thick polystyrene support which is

-6-

captivated within the housing. A plug and socket arrangement similar to the SMA connectors is used between stages. The spacing between stages, an important parameter in the performance, is not easily adjustable and was optimized at approximately 0.2 λ electrical length between $\lambda/4$ transformers by computer modeling of a two-stage amplifier. Some adjustment of this length is possible by changing the transformer dielectric.

III. Results

The three-stage amplifier was optimized utilizing a scalar network analyzer and an automatic noise measuring system utilizing an Apple II Plus computer. A Hewlett-Packard HP-346B calibrated noise diode connected to amplifier input through a calibrated HP-8493B, 20 dB attenuator was used as a noise standard; this was compared against a liquid-nitrogen noise standard and no significant error was found. For cooled measurements a cryogenic refrigerator [6] was utilized and the 20 dB attenuator was also cooled to decrease inaccuracy due to uncertainty of the noise diode and dewar input line loss and reflections.

In order to minimize the amplifier noise, the performance was measured for three different input $\lambda/4$ transformer slugs at three first-stage bias currents at 300K and 13K amplifier temperatures. These tests were performed for the Nippon Electric NE13783 and Mitsubishi MGF1403 transistors with resulting noise parameters given in Table I. These noise parameters refer to the three-stage amplifier and differ somewhat from the FET device noise parameters due to second and third stage noise. The reference plane for the parameters is at the gate-lead to package interface of the first stage.

The noise temperature, gain, input return loss, and output return loss of an optimum 3-stage amplifier without isolators are shown in Figure 3 for

-7-

	NE13	7*	MGF1	403†
	300К	1 3K	300K	13K
T _{min}	180 <u>+</u> 5	27 <u>+</u> 2	191 <u>+</u> 20	44 <u>+</u> 5
R _{opt}	5 <u>+</u> 1	3 <u>+</u> 1	5 <u>+</u> .6	4.5 <u>+</u> .6
X _{opt}	8 <u>+</u> 5	8 <u>+</u> 5	3 <u>+</u> 5	3 <u>+</u> 5
1/g _n	28 <u>+</u> 15	60 <u>+</u> 40	8 <u>+</u> 5	30 <u>+</u> 15
Z ₁ ΟΡΤ λ/4	15.8	12.2	15.8	15

*Biased at V_D = 4V and I_D = 8.7 mA @ 300K and 3.7 mA @ 13K. +Biased at V_D = 4V, I_D = 8.7 mA.

TABLE I - Measured Noise Parameters



Fig. 3. Noise temperature, gain, input return loss, and output return loss of optimized 3-stage amplifier without isolators.

both 300K and 13K operation. The amplifier is optimized for a 29K noise temperatu at band center and has an average noise temperature of 36K over a 1 GHz bandwidth. With slightly different tuning, a noise temperature of 26K was measured but less bandwidth was achieved. The amplifier is stable for any phase sliding short at input or output; however, an isolator may be necessary to improve input and output match, especially for wide band applications. Several commercial isolators specified for 243K to 358K operation, were tested at 13K and it was found that an Aertech unit [7] gave an input return loss of \geq 20 dB over a 10 to 11 GHz band but increased noise temperature to 36K.

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- [5] S. Weinreb, "Low-Noise Cooled GASFET Amplifiers," <u>IEEE Trans. on Microwave</u> <u>Theory and Technique</u>, vol. MTT-28, no. 10, October 1980, pp. 1041-1054.
- [6] CTI Cryogenics, Waltham, MA, model 1020 cryogenic refrigerator.
- [7] Aertech Industries, Inc., Sunnyvale, CA, model ASI-8012 isolator, S/N 723.



Appendix 1.A.





Appendix 1.E.

Appendix 1.D.



Appendix 1.G.

Appendix 1.F.



